## Search Notes

| Application/Control No. | Applicant(s)/Patent Under<br>Reexamination |
|-------------------------|--|
| 10666862                | SMIT ET AL.                                |
| Examiner                | Art Unit                                   |
| HIEP NGUYEN             | 3686                                       |

| SEARCHED |    |          |            |          |
|----------|----|----------|------------|----------|
| Class    |    | Subclass | Date       | Examiner |
| 705      | 03 |          | 10/20/2008 | HN       |

| SEARCH NOTES |          |
|--------------|----------|
| Date         | Examiner |
| 10/20/2008   | HN       |
|              |          |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

| /H. N./<br>Examiner.Art Unit 3686 |  |
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